## Search Notes



Application/Control	No.	

Applicant(s)/Patent Under Reexamination

10562547

DUFF ET AL.

Examiner
CEDRIC CHAN

Art Unit

## SEARCHED

Class	Subclass	Date	Examiner
422	100,62	4/23/2010	CC
436	55,180	4/23/2010	CC
222	52	4/23/2010	CC
73	1.36,1.74	4/23/2010	CC
700	28,32,37,89	4/23/2010	CC

SEARCH NOTES		
Search Notes	Date	Examiner
inventor search (PALM/EAST)	3/25/2010	CC
assignee search (see EAST Search History)	3/25/2010	CC
PCT Search Report of related International Application	3/25/2010	CC
keyword search US/FOR Databases	4/23/2010	CC
(EAST/EPO,JPO,DERWENT,USPAT,OCR,PGPUB)		
classification search with limiting text	4/23/2010	CC

	INTERFERENCE SEARCH		
Class	Subclass	Date	Examiner

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